

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	11768	((test\$ near memory) (BIST "built-in self-test" ("in circuit" near test\$3) LBIST MBIST)) and (test near (pattern patterns vector vectors data signals signal) near (generat\$3)) and ((physical and logical) near (address location cell cells addresses locations)) and ((conver\$5 RAM ROM EPROM EEPROM FLASH))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/29 17:12
S2	55309	test\$3 near memory	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/29 14:02
S3	36	test\$3 with memory	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/29 14:02
S4	8	((test\$3 with memory) and (test near (pattern patterns vector vectors data signals) near (generat\$3)) and ((physical and logical) near (address location cell cells addresses locations)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/29 14:18
S5	0	((test\$3 with memory) and (test near (pattern patterns vector vectors data signals) near (generat\$3)) and ((physical and logical) near (address location cell cells addresses locations)) and (conver\$5 near circuit))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/29 16:59
		((BIST "built-in self-test" ("in circuit" near test\$3) LBIST MBIST) and (test near (pattern patterns vector vectors data signals signal) near (generat\$3)) and ((physical and logical) near (address location cell cells addresses locations)) and ((conver\$5 RAM ROM EPROM EEPROM FLASH) near circuit)) and 714/738.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/29 17:10

S6	1	((BIST "built-in self-test" ("in circuit" near test\$3) LBIST MBIST) and (test near (pattern patterns vector vectors data signals signal) near (generat\$3)) and ((physical and logical) near (address location cell cells addresses locations)) and ((conver\$5 RAM ROM EPROM EEPROM FLASH) near circuit)) and 714/733.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/29 17:10
S7	2	(BIST "built-in self-test" ("in circuit" near test\$3) LBIST MBIST) and (test near (pattern patterns vector vectors data signals signal) near (generat\$3)) and ((physical and logical) near (address location cell cells addresses locations)) and ((conver\$5 RAM ROM EPROM EEPROM FLASH) near circuit)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/29 17:10
S8	36	(BIST "built-in self-test" ("in circuit" near test\$3) LBIST MBIST) and (test near (pattern patterns vector vectors data signals signal) near (generat\$3)) and ((physical and logical) near (address location cell cells addresses locations)) and ((conver\$5 RAM ROM EPROM EEPROM FLASH))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/29 17:10
S9	52	((test\$3 near memory) (BIST "built-in self-test" ("in circuit" near test\$3) LBIST MBIST)) and (test near (pattern patterns vector vectors data signals signal) near (generat\$3)) and ((physical and logical) near (address location cell cells addresses locations)) and ((conver\$5 RAM ROM EPROM EEPROM FLASH))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/29 17:12
S10	10	("4754215", "4862460", "5214654", "5314492", "5739778").pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/04/21 18:01
S11	2	"6065145".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/17 16:52
S12	1256	clock near align\$5	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/17 16:52

S13	1370	clock near align\$5	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/17 16:52
S14	9	(clock near align\$5) and (delay near test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/17 16:53